



## OUR TESTING NEEDS:

- need 2000+ working, burned-in parts
- must fab 8000-10000 die
- must do wafer probing to avoid packaging bad parts at \$25 each
- decision: do testing ourselves to avoid expense and headaches of interfacing with vendor
- testing must be:
  - at or near operating speed
  - minimal parametrics required
  - UNIX-based
  - quick and semi-automatic

## PREVIOUSLY AVAILABLE TESTERS:

### **ACADEMIC:**

not broadside

quite slow (50-200 KHz)

### **PRODUCTION TESTERS:**

very high through-put

comprehensive parametrics

very expensive (\$ 0.5-2 million)

### **LOGIC-ANALYZER BASED:**

affordable

intermediate performance

difficult to interface with UNIX  
(IEEE-488 , too slow)

### **Hewlett-Packard 6180**

50 MHz; 192 pins; 1Kbit/pin

\$1.7K / channel

PG only—company sells compatible SA

### **Hilevel Technology PG3700**

50MHz; 512 pins; 1,4, or 16 Kbit/pin

\$800 / channel

500 ps edge placement

Adjustable output voltages, many data formats

### **Integrated Measurement Systems (IMS)**

#### **Logic Master I**

20 MHz; 432 pins; 8Kbit/pin

\$460 / channel, controlled impedance test head

General-purpose translator for various workstations.

Many data formats (NRZ, RZ, R1, DNRZ) on 48 ch's

DC parametric measurement unit available

#### **Logic Master II**

Same as LM I, except:

16Kbit/pin, 1ns edge placement

\$650 / channel

Adjustable output levels

### **Northwest Instrument Systems 2300**

20 MHz (7 ch's-100MHz), 160 pins, 4Kbit/pin

\$330 / channel

NRZ only, 2ns edge placement

### **Tektronix 91S32 & 91P32**

25 MHz, 80 pins, 1Kbit/pin

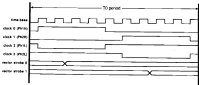
\$520 / channel (S32); \$415 / channel (P32)

Adjustable output levels on S32

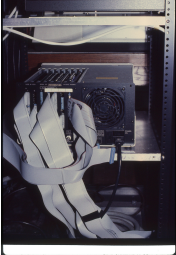


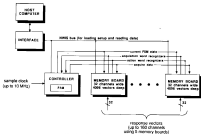


## Programming the PPS Pattern Generator



- select timebase: 10,20,...,100 needed in external
- select length of  $T_0$  period as 4 to 150 timebase cycles  
(normally,  $T_0$  period would correspond to 1000 cycles of CPU)
- program user clocks and vector strobes using time base granularity
- offset edges of PCLKs and strobes to 2 ns increments using tapped delay lines
- load test vectors, including stimulus modes, into 32-channel data boards
- assign a vector strobe to each 32-channel data board
- load starting vector number and repeat vector number into data boards
- go





## State Analyzer

## Programming the NWS State Analyzer

program the word recognizer RAM's on each 32-channel memory board; these cause the various 'acquisition word recognizer' and 'action word recognizer' lines to be asserted based on the values of the current response vector

program the finite state machine on the controller board; the 'action word recognizer' lines control branching among the 16 states of the FSM

in each state, the acquisition of the current response vector is defined according to the values of the 'acquisition word recognizer' lines

## For Our Application

the full capability of the FSM, which allows versatility equivalent to standard logic analyzers, was not necessary for our application

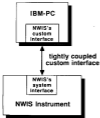
instead, we program the FSM to simply initialize at state 0 and remain there until the machine is halted

we program the acquisition word recognizers to store the response vector whenever a pre-designated input bit is 1; this input bit is connected to one of the pattern generator signals which is dedicated as 'acquisition enable'

### Limitations of NRETS Pattern Generator:

- no algorithmic pattern generation capability
- no control of rise and fall times for patterns or clocks
- no control of high and low logic levels
- signals can be tri-stated only by bytes, not per pin
- active edges of vector strobes must be separated by minimum 50 ns (maximum vector rate = 20 MHz)
- all signals are NRZ (non-return to zero), that is, each signal is either high, low, or high-Z from one vector strobe until the next vector strobe
- all 32 channels on one data board are strobed in unison, as defined by the vector strobe enabled on that board
- no mechanism for trading off pattern depth versus pattern width
- maximum pattern width is 160 channels
- maximum pattern depth is 8192 vectors (should be upgraded to 32k soon)

## NWIS APPROACH



## PROBLEMS

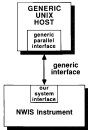
interface is tightly integrated  
into driver software

therefore not readily portable  
to other hosts

IBM-PC running MS-DOS is not  
suitable for integrated design -  
manufacture - test cycle

not feasible to bring test patterns  
from UNIX machine to PC

## OUR APPROACH



## ADVANTAGES

NWIS now lives on industry standard DR-11 interface

thus can be tightly coupled to UNIX machines where IC design files live

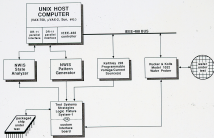
can control NWIS, water prober, power supplies, etc. from UNIX

## DISADVANTAGE

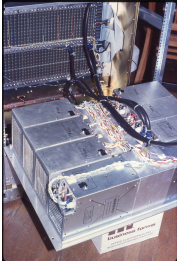
discarded NWIS's very nice interactive menus





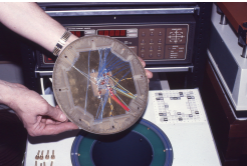


UNIX-NMIS Tester



### Test Program:

- 1) set-up State Analyzer
- 2) set-up clock discipline on Pattern Generator
- 3) get test vectors off disk, download to Pattern Generator
- 4) put all pins in test fixture to GND potential
- 5) prompt user to insert chip, enter its number
- 6) arm State Analyzer and Pattern Generator and de-assert Master Halt signal
- 7) wait for test to complete
- 8) put all pins at GND potential
- 9) prompt user to change chip
- 10) upload response vectors from State Analyzer
- 11) analyze response vectors, write files onto disk
- 12) go to Step 6







## COST (not incl. wafer probing):

### Monetary: (not including host computer)

Pattern Generator (36 channels) .....	\$17499
State Analyzer (36 channels) .....	9000
Test Head .....	7000
Load Boards for Test Head (3) .....	750
Programmable Power Supplies (2) .....	7500
Parallel Interface Boards (2) .....	700
IEEE Bus Controller .....	2000
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### Engineering Time:

Systems Programming .....	1 man-month
(drivers for parallel interfaces and IEEE-bus controller)	
Porting HW's code to UNIX .....	2 man-months
Additional UNIX applications code .....	1 man-month
Construction of rack .....	2 man-days
Customizing each load board .....	0.5 man-days